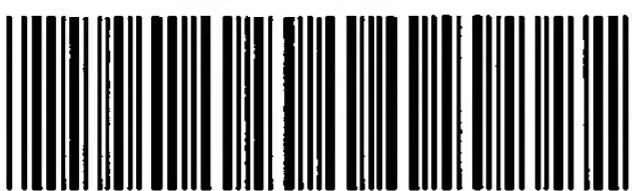


Search Notes**Application/Control No.**

10/656,651

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Art Unit

2685

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Class	Subclass	Date	Examiner
455	127.3	12/08/09	PJ
	a1		
	128		
	85-86		
	84		
	87-88		
	878.1		
	90.3		
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	103		
	66.1		
	67.11		
	67.13		
	880.1		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

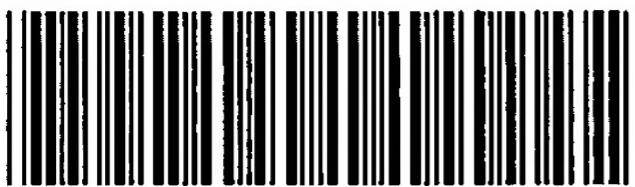
	DATE	EXMR
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Class	Subclass	Date	Examiner
455	127.3	12/08/09	PJ
	127.3		
	323		
	333		

Search Notes (continued)



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Art Unit

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2685

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Class	Subclass	Date	Examiner
458	50	12/18/10	AJ
323			
333		1	1
291			
511			
313-316			
341			
333	101		
104			
118-116			
330	310		
286			
277			
257	347		
352			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

INTERFERENCE SEARCHED

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner